Se	arch No	tes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/005,328	AYSAN ET AL.	
Examiner	Art Unit	
Tito Pham	2667	

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	389, 392	2/1/2006	TP
	401-405	2/1/2006	TP
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC		<b>')</b>
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